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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/549,865	07/28/2006	Victor Higgs	NAN165 US (8037)	4772
	7590 02/19/200 Patent Group LLP	EXAMINER		
18805 Cox Ave		AKANBI, ISIAKA O		
Suite 220 Saratoga, CA 9:	5070		ART UNIT	PAPER NUMBER
			2886	
			MAIL DATE	DELIVERY MODE
			02/19/2009	PAPER

Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

## Advisory Action Before the Filing of an Appeal Brief

Application No.	Applicant(s)		
10/549,865	HIGGS, VICTOR		
Examiner	Art Unit		
ISIAKA O. AKANBI	2886		

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The MAILING DATE of this communication appe	ears on the cover sheet with the c	correspondence add	ress
THE REPLY FILED <u>03 February 2009</u> FAILS TO PLACE THIS	APPLICATION IN CONDITION FO	R ALLOWANCE.	
1.  The reply was filed after a final rejection, but prior to or on application, applicant must timely file one of the following application in condition for allowance; (2) a Notice of Appfor Continued Examination (RCE) in compliance with 37 (periods:	replies: (1) an amendment, affidaviteal (with appeal fee) in compliance	t, or other evidence, w with 37 CFR 41.31; or	hich places the (3) a Request
<ul> <li>a) The period for reply expiresmonths from the mailing</li> <li>b) The period for reply expires on: (1) the mailing date of this A</li> </ul>	-	in the final rejection, whi	chever is later. In
no event, however, will the statutory period for reply expire I  Examiner Note: If box 1 is checked, check either box (a) or	ater than SIX MONTHS from the mailing	g date of the final rejection	n.
MONTHS OF THE FINAL REJECTION. See MPEP 706.07	f).		
Extensions of time may be obtained under 37 CFR 1.136(a). The date have been filed is the date for purposes of determining the period of ex under 37 CFR 1.17(a) is calculated from: (1) the expiration date of the set forth in (b) above, if checked. Any reply received by the Office later may reduce any earned patent term adjustment. See 37 CFR 1.704(b) NOTICE OF APPEAL	tension and the corresponding amount of shortened statutory period for reply origing than three months after the mailing date	of the fee. The appropria nally set in the final Offic	ate extension fee e action; or (2) as
2. The Notice of Appeal was filed on A brief in comp	liance with 37 CEP 41 37 must be t	filed within two months	of the date of
filing the Notice of Appeal (37 CFR 41.37(a)), or any exte Notice of Appeal has been filed, any reply must be filed w	nsion thereof (37 CFR 41.37(e)), to	avoid dismissal of the	
AMENDMENTS			
3. The proposed amendment(s) filed after a final rejection,  (a) They raise new issues that would require further co	nsideration and/or search (see NOT	<del></del>	cause
<ul> <li>(b) ☐ They raise the issue of new matter (see NOTE belo</li> <li>(c) ☐ They are not deemed to place the application in belo</li> </ul>	**	lucina or cimplifyina t	an incurse for
appeal; and/or			ie issues ioi
(d) They present additional claims without canceling a	corresponding number of finally reje	ected claims.	
NOTE: (See 37 CFR 1.116 and 41.33(a)).			
<ol> <li>The amendments are not in compliance with 37 CFR 1.1</li> <li>Applicant's reply has overcome the following rejection(s)</li> </ol>		mpliant Amendment (I	PTOL-324).
<ol> <li>Newly proposed or amended claim(s) would be all non-allowable claim(s).</li> </ol>	· · · · · · · · · · · · · · · · · · ·	imely filed amendmer	nt canceling the
7.  For purposes of appeal, the proposed amendment(s): a) how the new or amended claims would be rejected is protected. The status of the claim(s) is (or will be) as follows: Claim(s) allowed: Claim(s) objected to: Claim(s) rejected: 1-3 and 5-19. Claim(s) withdrawn from consideration:		l be entered and an e	xplanation of
AFFIDAVIT OR OTHER EVIDENCE			
<ol> <li>The affidavit or other evidence filed after a final action, but because applicant failed to provide a showing of good anwas not earlier presented. See 37 CFR 1.116(e).</li> </ol>			
<ol> <li>The affidavit or other evidence filed after the date of filing entered because the affidavit or other evidence failed to of showing a good and sufficient reasons why it is necessary</li> </ol>	overcome <u>all</u> rejections under appea y and was not earlier presented. Se	ll and/or appellant fail ee 37 CFR 41.33(d)(1	s to provide a ).
10. ☐ The affidavit or other evidence is entered. An explanatio REQUEST FOR RECONSIDERATION/OTHER	n of the status of the claims after er	ntry is below or attach	ed.
The request for reconsideration has been considered by See Continuation Sheet.	t does NOT place the application in	condition for allowan	ce because:
<ul> <li>12. ☐ Note the attached Information <i>Disclosure Statement</i>(s).</li> <li>13. ☐ Other:</li> </ul>	(PTO/SB/08) Paper No(s)		
/TARIFUR R CHOWDHURY/ Supervisory Patent Examiner, Art Unit 2886			

Continuation of 11. does NOT place the application in condition for allowance because: The applicant's arguments and the decoration, see page 7-12 have been fully considered but are not persuasive.

For the purpose of clarity and consistency, in the final rejection the examiner has obtained the paragraph numbers from the corresponding US publication (2004/0106217), which is consistent with the manner in which Non-final office action date May 27, 2008 paragraph were cited.

In response to Applicant's arguments that the cited reference Higgs does not disclose or even suggest or discuss a desire or need for or whether the laser could possibly heat the wafer sufficiently to " anneal the wafer or "a heating step to the semiconductor to diffuse contaminant from the particle into the semiconductor material". It is respectively pointed out to applicant that by applicant's own account (page 8, lines 13-14) Higgs excite the wafer/semiconductor to produced photoluminescence, which inherently anneal the wafer/semiconductor. Additionally, it is respectfully pointed out to applicant that it has been held that the absence of a disclosure in a prior art reference relating to function did not defeat the Board's finding of anticipation of claimed apparatus/device because the limitations at issue were found to be inherent in the prior art reference. In re Swinehart, 439 F.2d 210, 212-13, 169 USPQ 226, 228-29 (CCPA 1971).

Further, In response to Applicant's arguments that Higgs does not disclose both "annealing", and "after annealing ... exposing the surface ... to at least one high intensity beam of light" or "collecting photoluminescence twice, once before and once after the "heating step to the semiconductor to diffuse contaminant from the particle into the semiconductor material". It is respectfully pointed out to applicants that this arguments is not persuasive as Higgs clearly disclose in (pars. 000072-0072) that after laser excitation (the process of annealing (excited using laser excitation (to increase the energy (i.e. heat or power of semiconductor)(Annealing = a heat treatment that alters the microstructure of a material (i.e. semiconductor such as glass) causing changes in properties such as strength and hardness) and contaminated, and then/after the levels of contamination is confirmed, detected or determined for different images, inspection at an increase PL intensity is performed, and thus meet the limitations such as after annealing the semiconductor structure (excited using laser excitation (to increase the energy (i.e. heat or power of semiconductor), exposing the surface of the semiconductor structure in the vicinity of a surface particulate to at least one high-intensity beam of light from a suitable light source.

In response to Applicant's arguments that (i) a prima facie case has not been made, (ii) neither cited references disclose a "means to heat the sample under test associated with the support to diffuse contamination from a particulate into a semiconductor structure of the sample under test" or "heating means to heat the sample in situ, allowing a photoluminescence response to be measured before and after heating", as recited in claims 14, 15, 16, 17. It is respectfully pointed out to applicant that by applicant's own account the rejection was made as 103, and the examiner recognize that these limitations was not taught by Higgs but used Maris/Noguchi to find these limitations.

Further, cited reference Higgs is reasonably pertinent to the particular problem contamination with which the application was concerned [pars. 0005, 0016-17], therefore, it would have been at least obvious to one having ordinary skill in the art at the time of invention to modify Higgs by means to heat the sample in situ for the purpose of controlling the temperature of the sample with accuracy. Additionally, the examiner recognizes that obviousness can only be established by combining or modifying the teachings of the prior art to produce the claimed invention where there is some teaching, suggestion, or motivation to do so found either in the references themselves or in the knowledge generally available to one of ordinary skill in the art. See In re Fine, 837 F.2d 1071, 5 USPQ2d 1596 (Fed. Cir. 1988) and In re Jones, 958 F.2d 347, 21 USPQ2d 1941 (Fed. Cir. 1992). As such, the argument/remarks for request for reconsideration does not appear to place the application in condition for allowance.